



YOUSHANG SEMICONDUCTOR

设计研发新型功率器件

各类小信号开关

中低压及高压大电流等场效应管

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企业微信二维码



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Product Summary

BV _{DSS}	R _{DS(ON)} Max	I _D Max T _C = +25°C (Note 5)
60V	3.1mΩ @ V _{GS} = 10V	100A
	4.5mΩ @ V _{GS} = 4.5V	100A

Features

- Rated to +175°C – Ideal for High Ambient Temperature Environments
- 100% Unclamped Inductive Switching (UIS) Test in Production – Ensures More Reliable and Robust End Application
- Low R_{DS(ON)} – Minimizes Power Losses
- Low Q_g – Minimizes Switching Losses

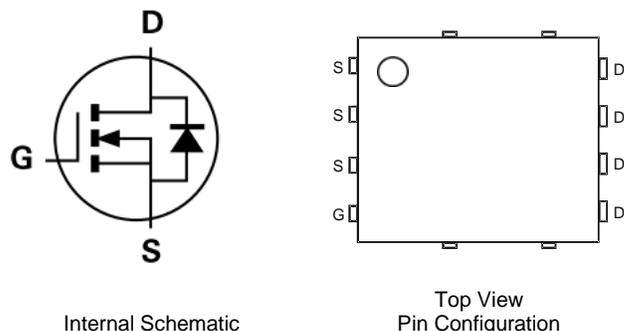
Description and Applications

This MOSFET is designed to meet the stringent requirements of automotive applications. It is qualified to AEC-Q101, supported by a PPAP and is ideal for use in:

- Primary switches in isolated DC-DC
- Synchronous rectifiers
- Load switches

Mechanical Data

- Package: PowerDI[®]5060-8
- Package Material: Molded Plastic, “Green” Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish – Matte Tin Annealed over Copper Leadframe; Solderable per MIL-STD-202, Method 208 (E3)
- Weight: 0.097 grams (Approximate)



Maximum Ratings (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Value	Unit	
Drain-Source Voltage	V_{DSS}	60	V	
Gate-Source Voltage	V_{GSS}	± 20	V	
Continuous Drain Current (Note 6)	I_D	$T_A = +25^\circ\text{C}$ $T_A = +70^\circ\text{C}$	22 16	A
Continuous Drain Current (Notes 5 & 7)		$T_C = +25^\circ\text{C}$ $T_C = +100^\circ\text{C}$	100 100	A
Maximum Continuous Body Diode Forward Current (Note 6)	I_S	100	A	
Pulsed Drain Current (10 μs Pulse, Duty Cycle = 1%)	I_{DM}	400	A	
Pulsed Body Diode Forward Current (10 μs Pulse, Duty Cycle = 1%)	I_{SM}	400	A	
Avalanche Current, $L = 0.2\text{mH}$	I_{AS}	40	A	
Avalanche Energy, $L = 0.2\text{mH}$	E_{AS}	160	mJ	

Thermal Characteristic

Characteristic	Symbol	Value	Unit	
Total Power Dissipation (Note 6)	P_D	$T_A = +25^\circ\text{C}$	2.6	W
Thermal Resistance, Junction to Ambient (Note 6)		$R_{\theta JA}$	47	$^\circ\text{C/W}$
Total Power Dissipation (Note 7)	P_D	$T_C = +25^\circ\text{C}$	138	W
Thermal Resistance, Junction to Case (Note 7)		$R_{\theta JC}$	0.9	$^\circ\text{C/W}$
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +175	$^\circ\text{C}$	

- Notes:
5. Limited by package.
 6. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.
 7. Thermal resistance from junction to soldering point (on the exposed drain pad).

Electrical Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV _{DSS}	60	—	—	V	V _{GS} = 0V, I _D = 1mA
Zero Gate Voltage Drain Current	I _{DSS}	—	—	1	μA	V _{DS} = 48V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	V _{GS(TH)}	1	—	3	V	V _{DS} = V _{GS} , I _D = 250μA
Static Drain-Source On-Resistance	R _{DS(ON)}	—	2.5	3.1	mΩ	V _{GS} = 10V, I _D = 25A
		—	3.3	4.5	mΩ	V _{GS} = 4.5V, I _D = 20A
Diode Forward Voltage	V _{SD}	—	—	1.3	V	V _{GS} = 0V, I _S = 25A
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C _{iss}	—	5399	—	pF	V _{DS} = 30V, V _{GS} = 0V f = 1MHz
Output Capacitance	C _{oss}	—	1306	—		
Reverse Transfer Capacitance	C _{rss}	—	92	—		
Gate Resistance	R _g	—	0.64	—	Ω	V _{DS} = 0V, V _{GS} = 0V, f = 1MHz
Total Gate Charge (V _{GS} = 10V)	Q _g	—	78.3	—	nC	V _{DD} = 30V, I _D = 25A
Total Gate Charge (V _{GS} = 4.5V)	Q _g	—	38.5	—		
Gate-Source Charge	Q _{gs}	—	10.2	—		
Gate-Drain Charge	Q _{gd}	—	20.4	—		
Turn-On Delay Time	t _{D(ON)}	—	9.9	—	ns	V _{DD} = 30V, V _{GS} = 10V I _D = 25A, R _g = 3.5Ω
Turn-On Rise Time	t _r	—	17.7	—		
Turn-Off Delay Time	t _{D(OFF)}	—	53.5	—		
Turn-Off Fall Time	t _f	—	32.9	—		
Body Diode Reverse Recovery Time	t _{RR}	—	49.7	—	ns	I _F = 25A, di/dt = 100A/μs
Body Diode Reverse Recovery Charge	Q _R	—	78.9	—	nC	

Notes: 8. Short duration pulse test used to minimize self-heating effect.
 9. Guaranteed by design. Not subject to production testing.

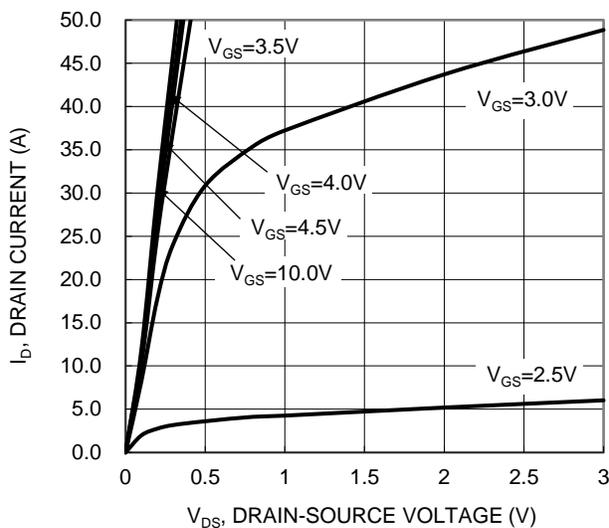


Figure 1. Typical Output Characteristic

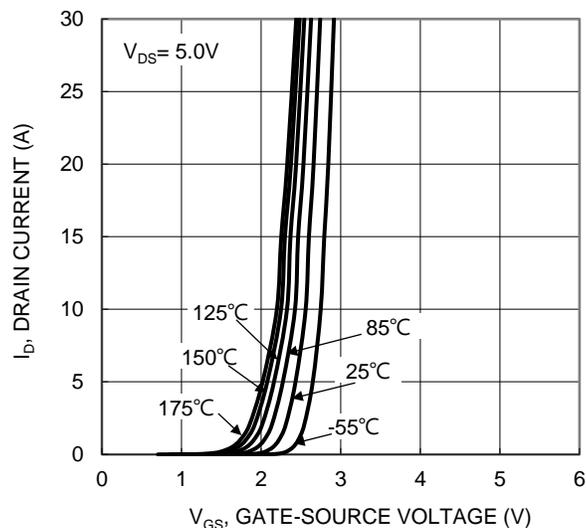


Figure 2. Typical Transfer Characteristic

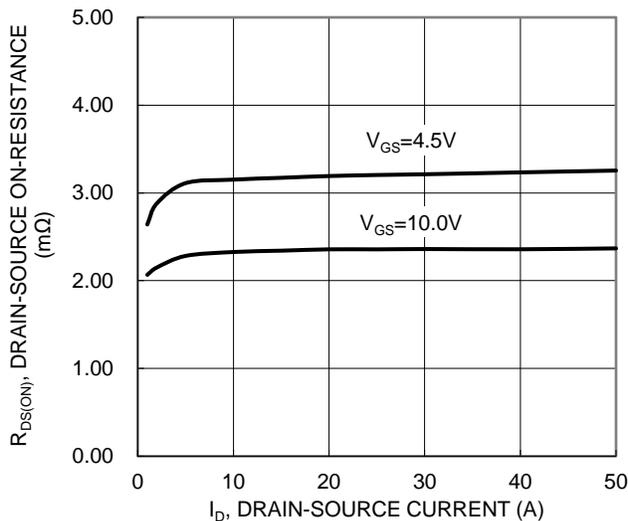


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

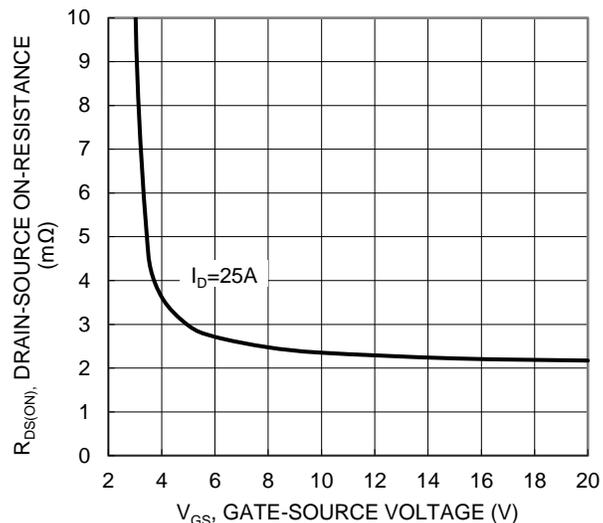


Figure 4. Typical Transfer Characteristic

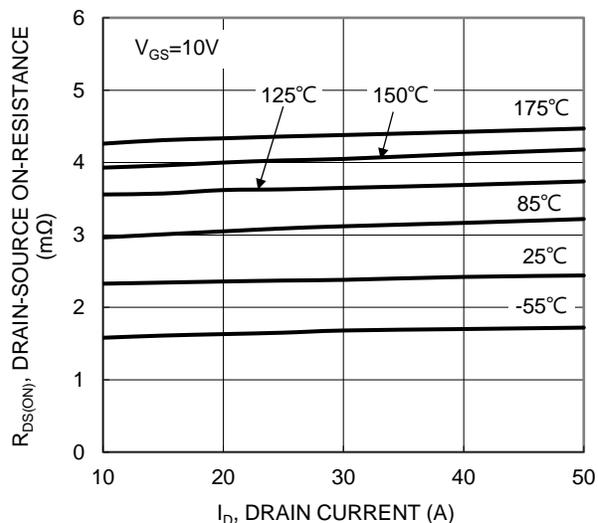


Figure 5. Typical On-Resistance vs. Drain Current and Temperature

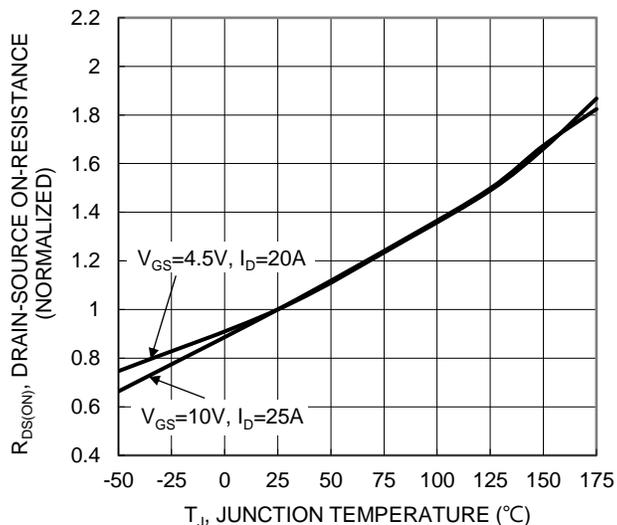


Figure 6. On-Resistance Variation with Temperature

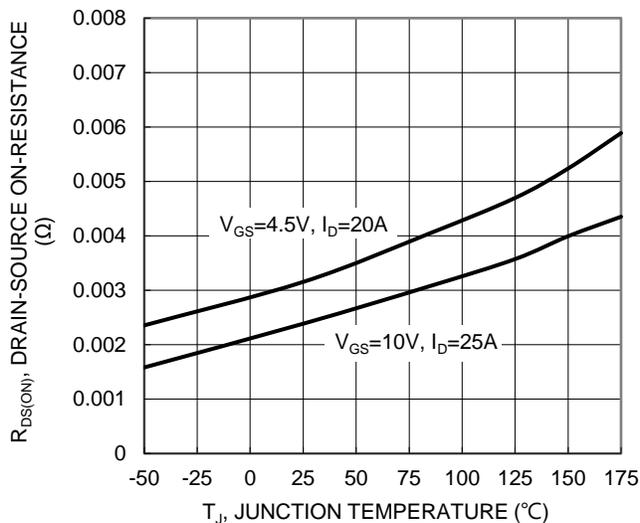


Figure 7. On-Resistance Variation with Temperature

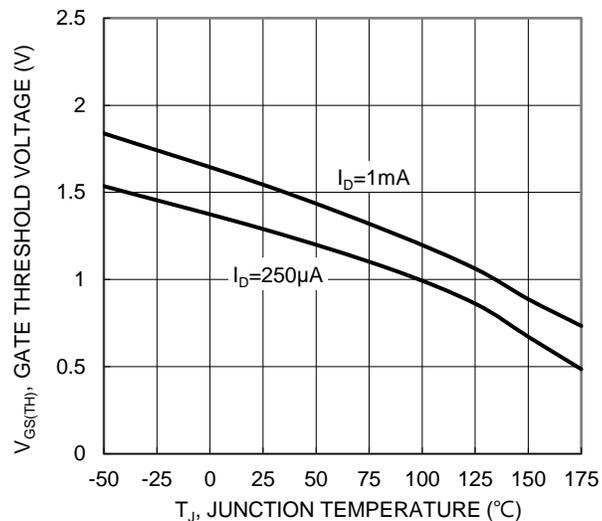


Figure 8. Gate Threshold Variation vs. Temperature

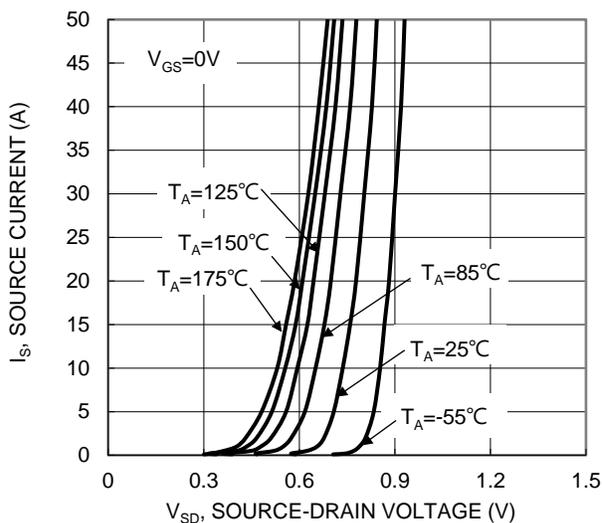


Figure 9. Diode Forward Voltage vs. Current

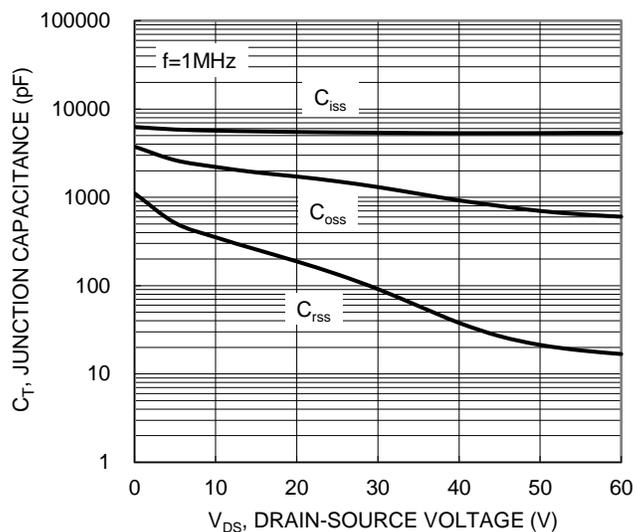


Figure 10. Typical Junction Capacitance

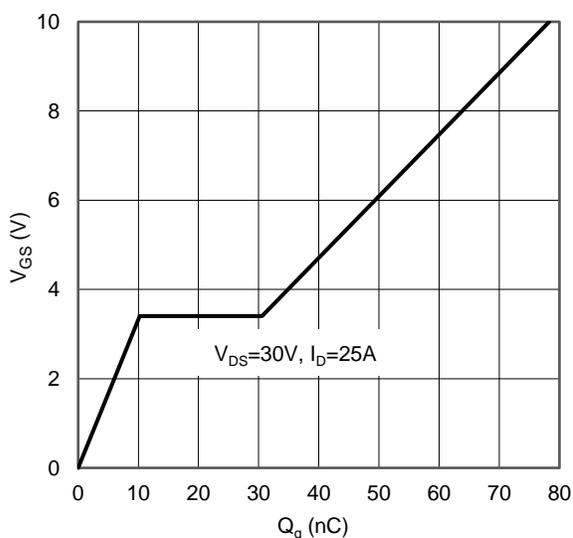


Figure 11. Gate Charge

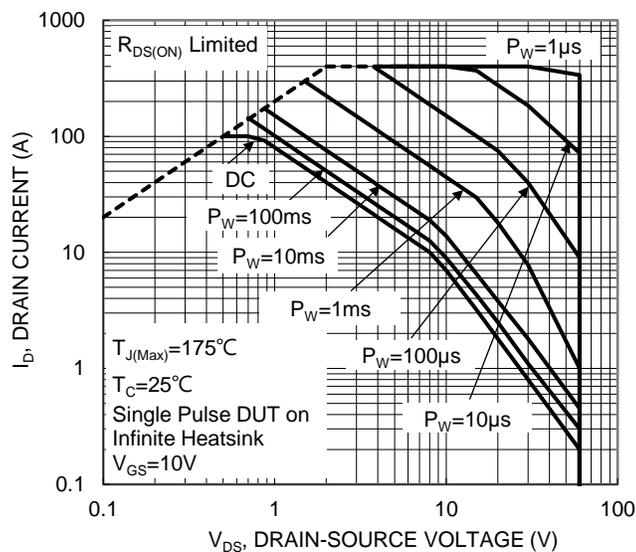


Figure 12. SOA, Safe Operation Area

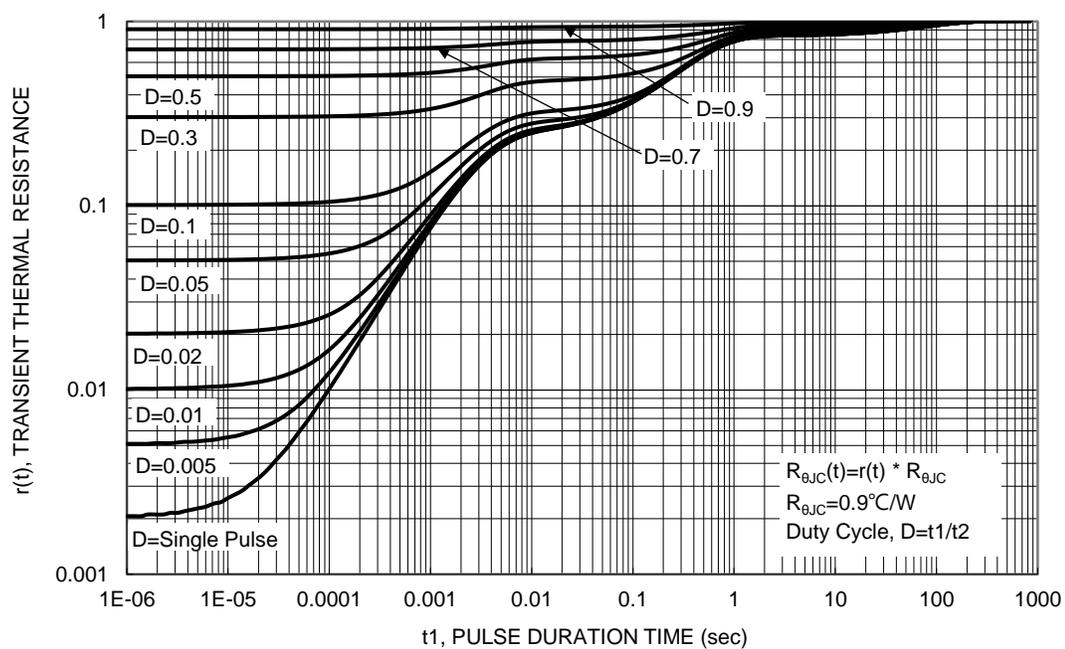
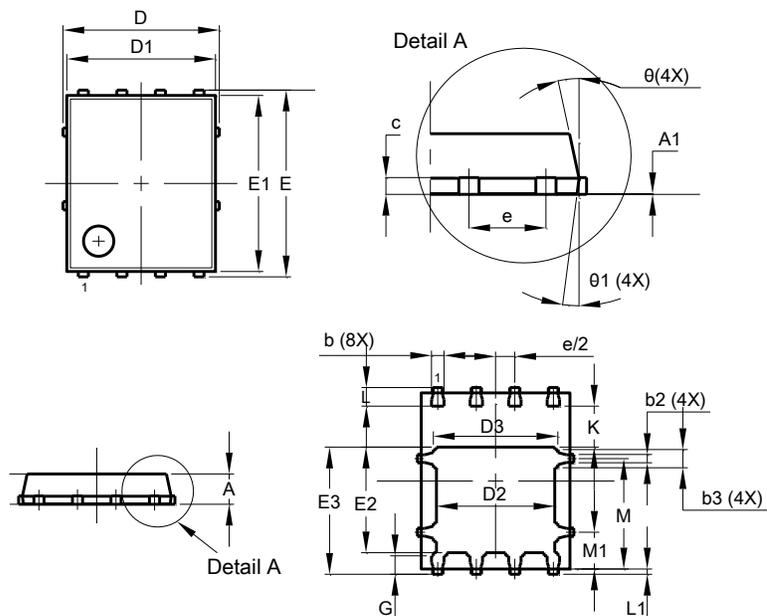


Figure 13. Transient Thermal Resistance

Package Outline Dimensions

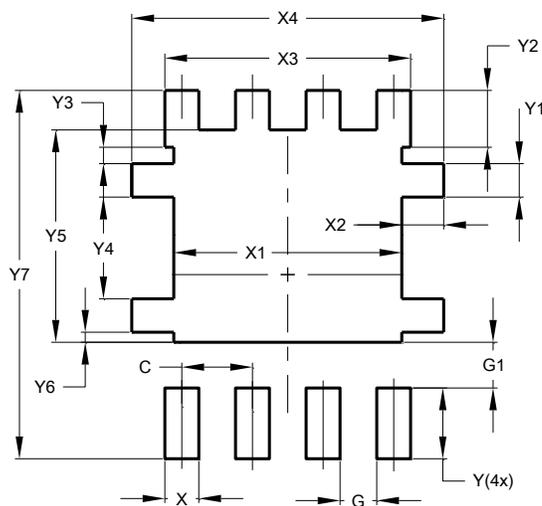
PowerDI5060-8



PowerDI5060-8			
Dim	Min	Max	Typ
A	0.90	1.10	1.00
A1	0.00	0.05	—
b	0.33	0.51	0.41
b2	0.200	0.350	0.273
b3	0.40	0.80	0.60
c	0.230	0.330	0.277
D	5.15 BSC		
D1	4.70	5.10	4.90
D2	3.70	4.10	3.90
D3	3.90	4.30	4.10
E	6.15 BSC		
E1	5.60	6.00	5.80
E2	3.28	3.68	3.48
E3	3.99	4.39	4.19
e	1.27 BSC		
G	0.51	0.71	0.61
K	0.51	—	—
L	0.51	0.71	0.61
L1	0.100	0.200	0.175
M	3.235	4.035	3.635
M1	1.00	1.40	1.21
θ	10°	12°	11°
$\theta1$	6°	8°	7°
All Dimensions in mm			

Suggested Pad Layout

PowerDI5060-8



Dimensions	Value (in mm)
C	1.270
G	0.660
G1	0.820
X	0.610
X1	4.100
X2	0.755
X3	4.420
X4	5.610
Y	1.270
Y1	0.600
Y2	1.020
Y3	0.295
Y4	1.825
Y5	3.810
Y6	0.180
Y7	6.610